

TOSHIBA Transistor Silicon NPN Epitaxial Type

# 2SC5714

High-Speed Switching Applications  
 DC-DC Converter Applications  
 Strobe Applications

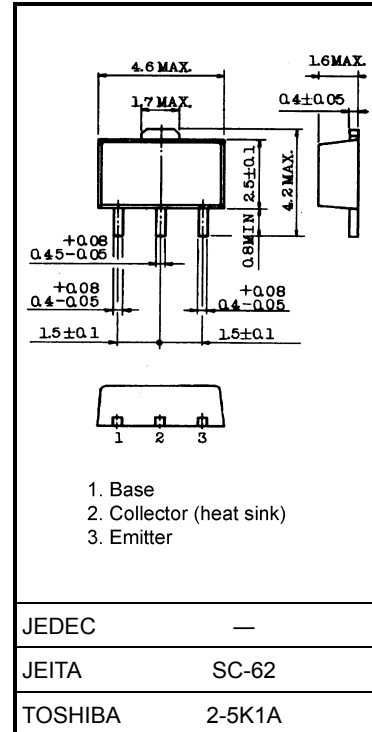
- High DC current gain:  $h_{FE} = 400$  to  $1000$  ( $I_C = 0.5$  A)
- Low collector-emitter saturation voltage:  $V_{CE(sat)} = 0.15$  V (max)
- High-speed switching:  $t_f = 90$  ns (typ.)

### Absolute Maximum Ratings ( $T_a = 25^\circ\text{C}$ )

Characteristics	Symbol	Rating	Unit
Collector-base voltage	$V_{CB0}$	40	V
Collector-emitter voltage	$V_{CEX}$	30	V
Collector-emitter voltage	$V_{CEO}$	20	V
Emitter-base voltage	$V_{EBO}$	7	V
Collector current	DC	$I_C$	4
	Pulse	$I_{CP}$	7
Base current	$I_B$	400	mA
Collector power dissipation	DC	$P_C$	1.0
	$t = 10$ s	(Note 1)	2.5
Junction temperature	$T_j$	150	$^\circ\text{C}$
Storage temperature range	$T_{stg}$	-55 to 150	$^\circ\text{C}$

Industrial Applications

Unit: mm



Weight: 0.05 g (typ.)

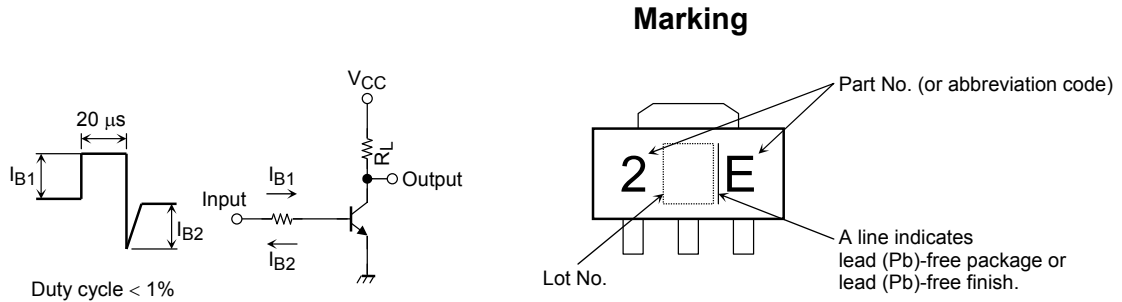
Note 1: Mounted on an FR4 board (glass epoxy, 1.6 mm thick, Cu area: 645 mm<sup>2</sup>)

Note 2: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

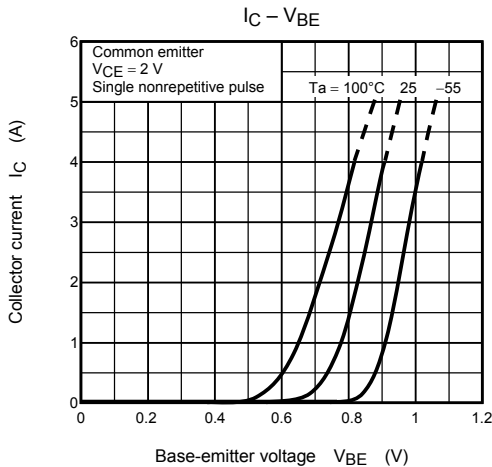
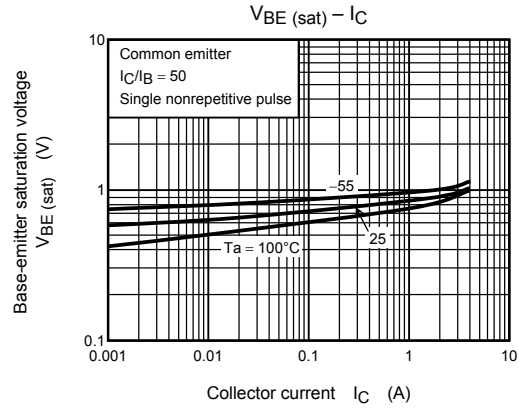
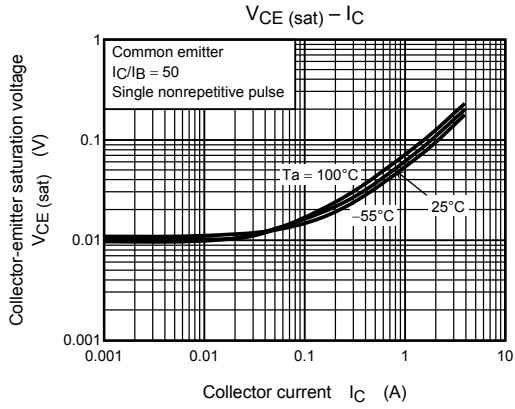
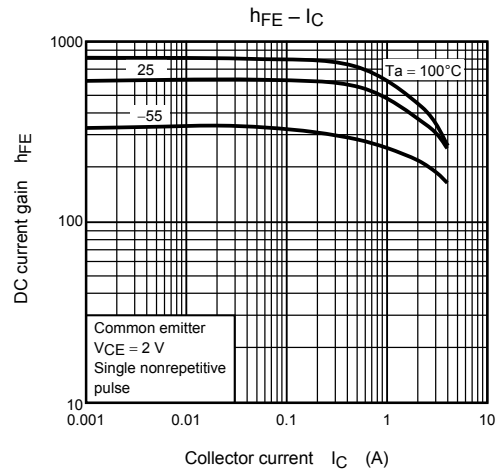
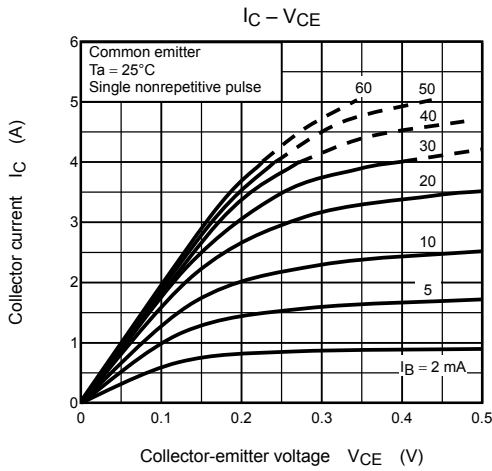
Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

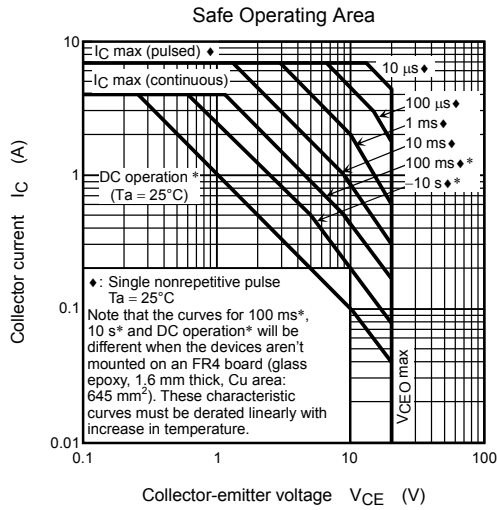
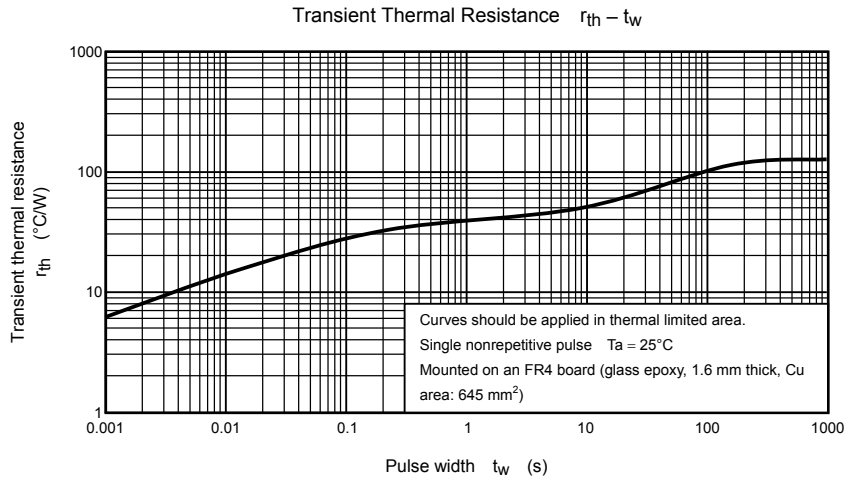
**Electrical Characteristics (Ta = 25°C)**

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit	
Collector cut-off current	$I_{CBO}$	$V_{CB} = 40\text{ V}, I_E = 0$	—	—	100	nA	
Emitter cut-off current	$I_{EBO}$	$V_{EB} = 7\text{ V}, I_C = 0$	—	—	100	nA	
Collector-emitter breakdown voltage	$V_{(BR) CEO}$	$I_C = 10\text{ mA}, I_B = 0$	20	—	—	V	
DC current gain	$h_{FE} (1)$	$V_{CE} = 2\text{ V}, I_C = 0.5\text{ A}$	400	—	1000		
	$h_{FE} (2)$	$V_{CE} = 2\text{ V}, I_C = 1.6\text{ A}$	200	—	—		
Collector-emitter saturation voltage	$V_{CE (sat)}$	$I_C = 1.6\text{ A}, I_B = 32\text{ mA}$	—	—	0.15	V	
Base-emitter saturation voltage	$V_{BE (sat)}$	$I_C = 1.6\text{ A}, I_B = 32\text{ mA}$	—	—	1.10	V	
Collector output capacitance	$C_{ob}$	$V_{CB} = 10\text{ V}, I_E = 0, f = 1\text{ MHz}$	—	18	—	pF	
Switching time	Rise time	$t_r$	See Figure 1 circuit diagram.			—	ns
	Storage time	$t_{stg}$	$V_{CC} \approx 12\text{ V}, R_L = 7.5\ \Omega$			—	
	Fall time	$t_f$	$I_{B1} = -I_{B2} = 53.3\text{ mA}$			—	



**Figure 1 Switching Time Test Circuit & Timing Chart**





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